


<b>Search Notes</b>  	<b>Application/Control No.</b>  10576899	<b>Applicant(s)/Patent Under Reexamination</b>  PAILA ET AL.
	<b>Examiner</b>  MARCOS BATISTA	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
370	329	5/13/2008	mb
370	314	5/13/2008	mb
455	343.1-343.4	12/2/2008	mb
713	300, 323, 320, 324	12/2/2008	mb

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with TA - Yogesh Aggarwal	5/13/2008	mb
Consulted with Lun-YI Lao	5/13/2008	mb
East Search	5/13/2008	mb
Inventor's Name Search	5/13/2008	mb
East Search	12/2/2008	mb
Consulted with Rafael Perez Gutierrez	3/17/2009	mb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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